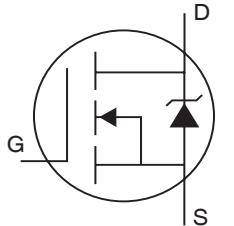
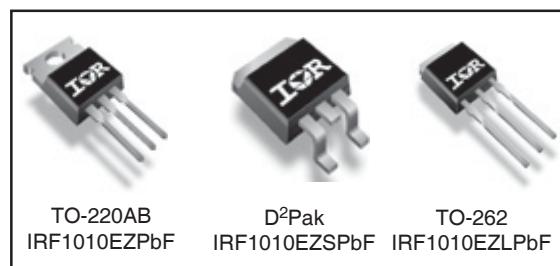


AUTOMOTIVE MOSFET

IRF1010EZPbF
IRF1010EZSPbF
IRF1010EZLPbF

HEXFET® Power MOSFET

	$V_{DSS} = 60V$ $R_{DS(on)} = 8.5m\Omega$ $I_D = 75A$
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Features

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	84	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (See Fig. 9)	60	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	75	
I_{DM}	Pulsed Drain Current ①	340	
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	140	W
	Linear Derating Factor	0.90	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	99	mJ
E_{AS} (tested)	Single Pulse Avalanche Energy Tested Value ⑦	180	
I_{AR}	Avalanche Current ①	See Fig.12a,12b,15,16	A
E_{AR}	Repetitive Avalanche Energy ⑥		mJ
T_J	Operating Junction and	-55 to + 175	°C
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf·in (1.1N·m)	

Thermal Resistance

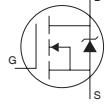
	Parameter	Typ.	Max.	Units
R_{0JC}	Junction-to-Case	—	1.11	°C/W
R_{0CS}	Case-to-Sink, Flat, Greased Surface	0.50	—	
R_{0JA}	Junction-to-Ambient	—	62	
R_{0JA}	Junction-to-Ambient (PCB Mount, steady state)⑧	—	40	

HEXFET® is a registered trademark of International Rectifier.

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	60	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.058	—	V/ $^{\circ}\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	—	6.8	8.5	$\text{m}\Omega$	$V_{GS} = 10V, I_D = 51\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 100\mu\text{A}$
g_{fs}	Forward Transconductance	200	—	—	S	$V_{DS} = 25V, I_D = 51\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	20	μA	$V_{DS} = 60V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 60V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	200		$V_{GS} = -20V$
Q_g	Total Gate Charge	—	58	86	nC	$I_D = 51\text{A}$
Q_{gs}	Gate-to-Source Charge	—	19	28		$V_{DS} = 48V$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	21	32		$V_{GS} = 10V$ ④
$t_{d(on)}$	Turn-On Delay Time	—	19	—	ns	$V_{DD} = 30V$
t_r	Rise Time	—	90	—		$I_D = 51\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	38	—		$R_G = 7.95\Omega$
t_f	Fall Time	—	54	—		$V_{GS} = 10V$ ④
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_s	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	2810	—		
C_{oss}	Output Capacitance	—	420	—	pF	$V_{GS} = 0V$
C_{rss}	Reverse Transfer Capacitance	—	200	—		$V_{DS} = 25V$
C_{oss}	Output Capacitance	—	1440	—		$f = 1.0\text{MHz}$, See Fig. 5
C_{oss}	Output Capacitance	—	320	—		$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	510	—		$V_{GS} = 0V, V_{DS} = 48V, f = 1.0\text{MHz}$
						$V_{GS} = 0V, V_{DS} = 0V \text{ to } 48V$

Diode Characteristics

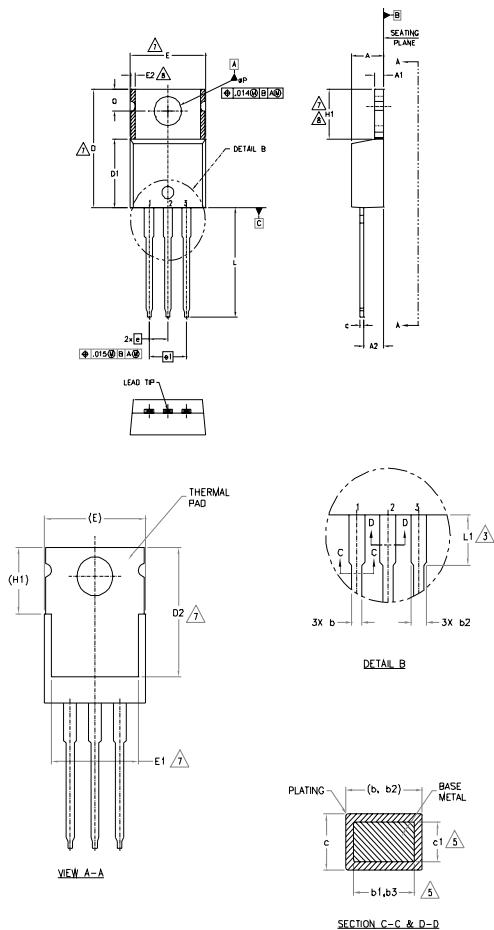
	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	84	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	340		
V_{SD}	Diode Forward Voltage	—	—	1.3		$T_J = 25^\circ\text{C}, I_S = 51\text{A}, V_{GS} = 0V$ ④
t_{rr}	Reverse Recovery Time	—	41	62	ns	$T_J = 25^\circ\text{C}, I_F = 51\text{A}, V_{DD} = 30V$
Q_{rr}	Reverse Recovery Charge	—	54	81	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by $T_{J\text{max}}$, starting $T_J = 25^\circ\text{C}$, $L = 0.077\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 51\text{A}$, $V_{GS} = 10V$. Part not recommended for use above this value.
- ③ $I_{SD} \leq 51\text{A}$, $di/dt \leq 260\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 175^\circ\text{C}$.
- ④ Pulse width $\leq 1.0\text{ms}$; duty cycle $\leq 2\%$.
- ⑤ $C_{oss \text{ eff.}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑥ Limited by $T_{J\text{max}}$, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑦ This value determined from sample failure population. 100% tested to this value in production.
- ⑧ This is applied to D²Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



NOTES

- 1 - DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
- 2 - DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- 3 - LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
- 4 - DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5 - DIMENSION b1, b3 & c1 APPLY TO BASE METAL ONLY.
- 6 - CONTROLLING DIMENSION INCHES.
- 7 - THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E1, H1, D2 & E1
- 8 - DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- 9 - OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	DIMENSIONS				NOTES
	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
A	3.56	4.83	.140	.190	
A1	0.51	1.40	.020	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0.38	0.97	.015	.038	5
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
c	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	-	.030	8
e	2.54 BSC		100 BSC		
e1	5.08 BSC		200 BSC		7,8
H1	5.84	6.86	.230	.270	
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
oP	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

LEAD ASSIGNMENTS

HEXFET

- 1 - GATE
- 2 - DRAIN
- 3 - SOURCE

KITS-C-PACK

- 1 - GATE
- 2 - COLLECTOR
- 3 - EMITTER

DIODES

- 1 - ANODE
- 2 - CATHODE
- 3 - ANODE

TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010
LOT CODE 1789
ASSEMBLED ON WW 19, 2000
IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position
indicates "Lead - Free"

